

<b>Search Notes</b> 	<b>Application/Control No.</b> 09/765,670	<b>Applicant(s)/Patent under Reexamination</b> MURAYAMA ET AL.
	<b>Examiner</b> Andrew Lee	<b>Art Unit</b> 2616

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner